

BUK9K35-60E

Dual N-channel TrenchMOS logic level FET

23 April 2013

Product data sheet

1. General description

Dual logic level N-channel MOSFET in a LPAK56D package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

2. Features and benefits

- Q101 compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with $V_{GS(th)} > 0.5 \text{ V @ } 175 \text{ °C}$

3. Applications

- 12 V Automotive systems
- Motors, lamps and solenoid control
- Start-stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|--|----------------------------------|--|-----|------|-----|------|
| V_{DS} | drain-source voltage | $T_j \geq 25 \text{ °C}; T_j \leq 175 \text{ °C}$ | - | - | 60 | V |
| I_D | drain current | $V_{GS} = 5 \text{ V}; T_{mb} = 25 \text{ °C}; \text{Fig. 1}$ | - | - | 22 | A |
| P_{tot} | total power dissipation | $T_{mb} = 25 \text{ °C}; \text{Fig. 2}$ | - | - | 38 | W |
| Static characteristics FET1 and FET2 | | | | | | |
| $R_{DS(on)}$ | drain-source on-state resistance | $V_{GS} = 5 \text{ V}; I_D = 5 \text{ A}; T_j = 25 \text{ °C}; \text{Fig. 12}$ | - | 30.5 | 35 | mΩ |
| Dynamic characteristics FET1 and FET2 | | | | | | |
| Q_{GD} | gate-drain charge | $I_D = 5 \text{ A}; V_{DS} = 48 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 25 \text{ °C}; \text{Fig. 14}; \text{Fig. 15}$ | - | 3 | - | nC |

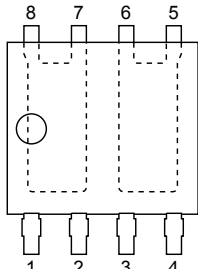
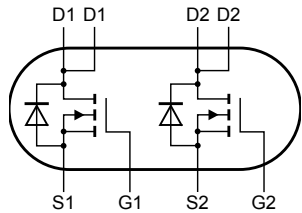


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5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|-------------|--|--|
| 1 | S1 | source1 |  <p>LFPAK56D (SOT1205)</p> |  <p><i>mbk725</i></p> |
| 2 | G1 | gate1 | | |
| 3 | S2 | source2 | | |
| 4 | G2 | gate2 | | |
| 5 | D2 | drain2 | | |
| 6 | D2 | drain2 | | |
| 7 | D1 | drain1 | | |
| 8 | D1 | drain1 | | |

6. Ordering information

Table 3. Ordering information

| Type number | Package | | |
|-------------|----------|--|---------|
| | Name | Description | Version |
| BUK9K35-60E | LFPAK56D | Plastic single ended surface mounted package (LFPAK56D); 8 leads | SOT1205 |

7. Marking

Table 4. Marking codes

| Type number | Marking code |
|-------------|--------------|
| BUK9K35-60E | 9356E |

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-----------|----------------------|---|------------|-----|------|
| V_{DS} | drain-source voltage | $T_j \geq 25\text{ }^\circ\text{C}$; $T_j \leq 175\text{ }^\circ\text{C}$ | - | 60 | V |
| V_{DGR} | drain-gate voltage | $R_{GS} = 20\text{ k}\Omega$; $T_j \geq 25\text{ }^\circ\text{C}$; $T_j \leq 175\text{ }^\circ\text{C}$ | - | 60 | V |
| V_{GS} | gate-source voltage | $T_j \leq 175\text{ }^\circ\text{C}$; DC | -10 | 10 | V |
| | | $T_j \leq 175\text{ }^\circ\text{C}$ | [1][2] -15 | 15 | V |
| I_D | drain current | $T_{mb} = 25\text{ }^\circ\text{C}$; $V_{GS} = 5\text{ V}$; Fig. 1 | - | 22 | A |
| | | $T_{mb} = 100\text{ }^\circ\text{C}$; $V_{GS} = 5\text{ V}$; Fig. 1 | - | 16 | A |
| I_{DM} | peak drain current | $T_{mb} = 25\text{ }^\circ\text{C}$; pulsed; $t_p \leq 10\text{ }\mu\text{s}$; Fig. 4 | - | 90 | A |

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---|--|---|------------------------|-----|---------|
| P_{tot} | total power dissipation | $T_{mb} = 25\text{ °C}$; Fig. 2 | - | 38 | W |
| T_{stg} | storage temperature | | -55 | 175 | °C |
| T_j | junction temperature | | -55 | 175 | °C |
| $T_{sld(M)}$ | peak soldering temperature | | - | 260 | °C |
| Source-drain diode FET1 and FET2 | | | | | |
| I_S | source current | $T_{mb} = 25\text{ °C}$ | - | 22 | A |
| I_{SM} | peak source current | pulsed; $t_p \leq 10\text{ }\mu\text{s}$; $T_{mb} = 25\text{ °C}$ | - | 90 | A |
| Avalanche Ruggedness FET1 and FET2 | | | | | |
| $E_{DS(AL)S}$ | non-repetitive drain-source avalanche energy | $I_D = 22\text{ A}$; $V_{sup} \leq 60\text{ V}$; $V_{GS} = 5\text{ V}$; $T_{j(init)} = 25\text{ °C}$; Fig. 3 | [3][4] | - | 19.5 mJ |

- [1] Accumulated Pulse duration up to 50 hours delivers zero defect ppm.
- [2] Significantly longer life times are achieved by lowering T_j and or V_{GS}
- [3] Refer to application note AN10273 for further information
- [4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C

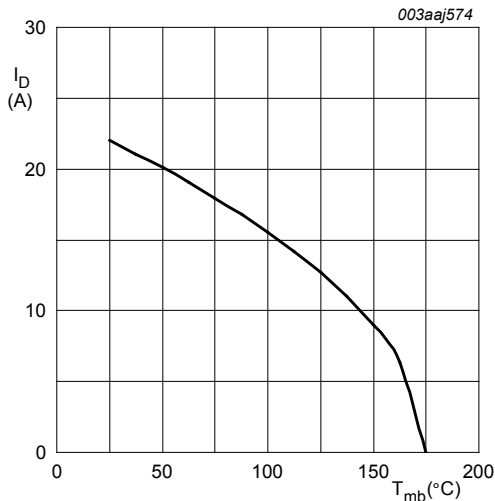


Fig. 1. Continuous drain current as a function of mounting base temperature

$$V_{GS} \geq 5V$$

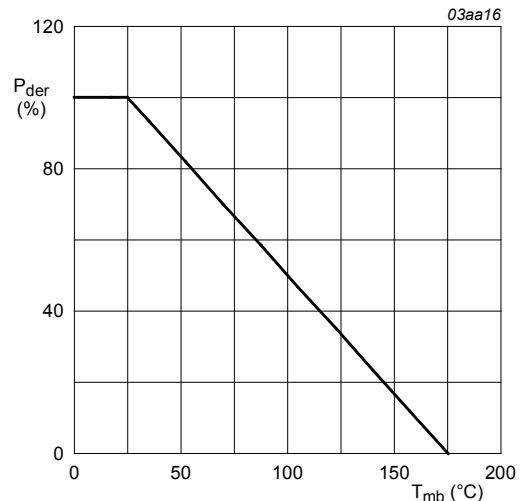


Fig. 2. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25\text{ °C})}} \times 100\%$$

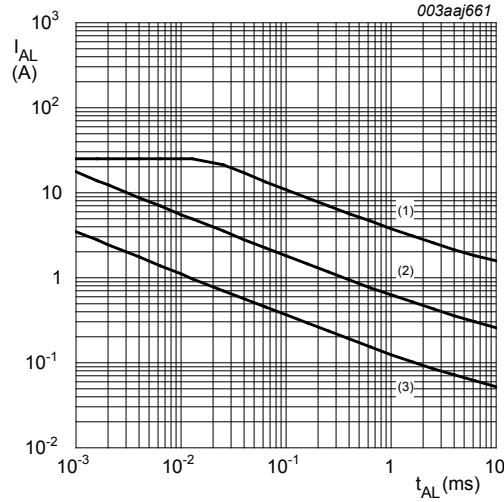


Fig. 3. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time, FET1 and FET2

- (1) Single-pulse; $T_j = 25\text{ }^\circ\text{C}$.
- (2) Single-pulse; $T_j = 150\text{ }^\circ\text{C}$.
- (3) Repetitive.

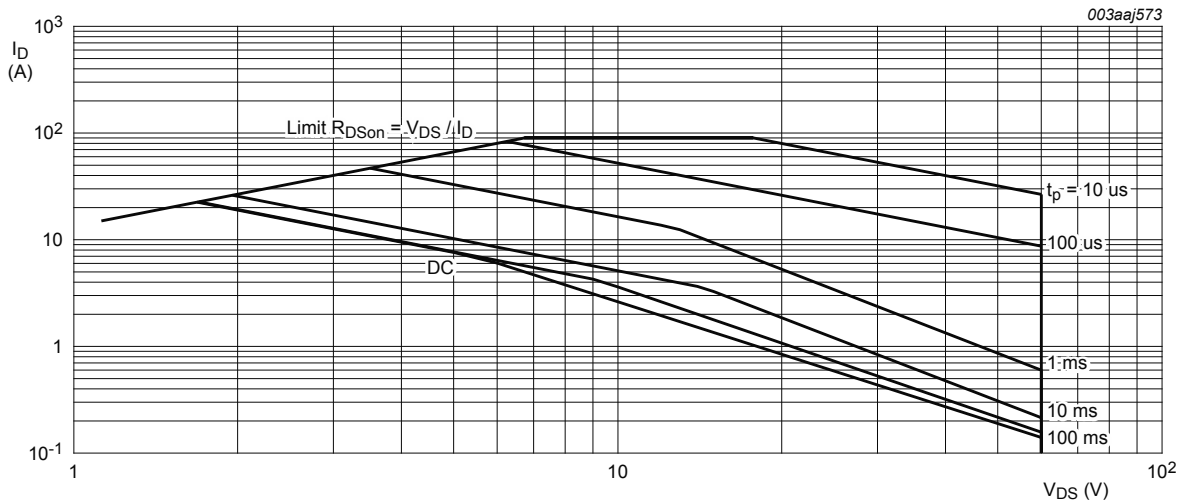


Fig. 4. Safe operating area; continuous and peak drain current as a function of drain-source voltage

$T_{mb} = 25\text{ }^\circ\text{C}$; I_{DM} is single pulse

9. Thermal characteristics

Table 6. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|----------------|---|------------|-----|-----|------|------|
| $R_{th(j-mb)}$ | thermal resistance from junction to mounting base | Fig. 5 | - | - | 3.96 | K/W |

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---------------|---|---|-----|-----|-----|------|
| $R_{th(j-a)}$ | thermal resistance from junction to ambient | Minimum footprint; mounted on a printed circuit board | - | 95 | - | K/W |

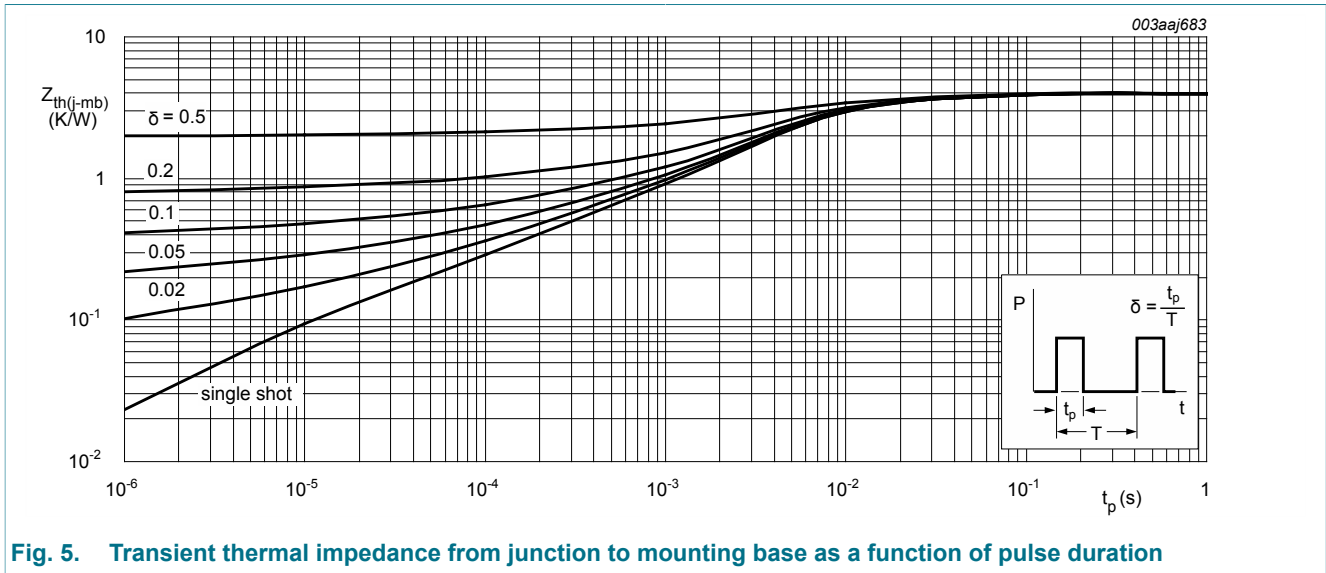


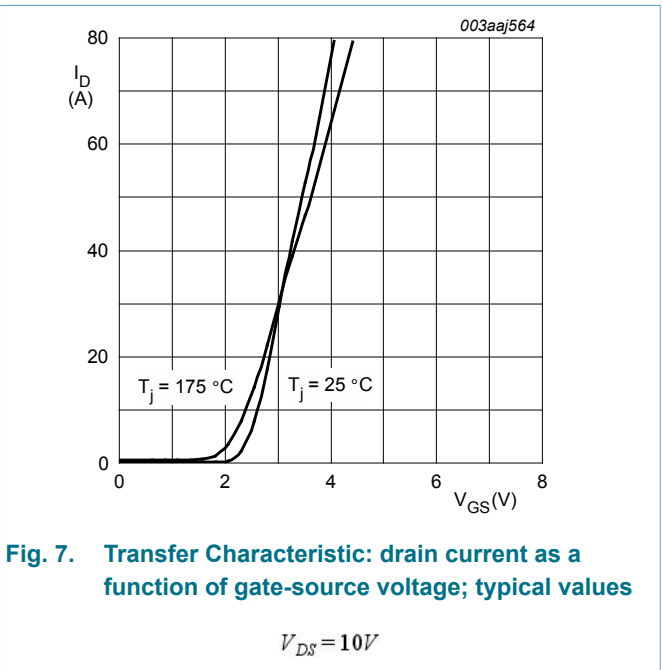
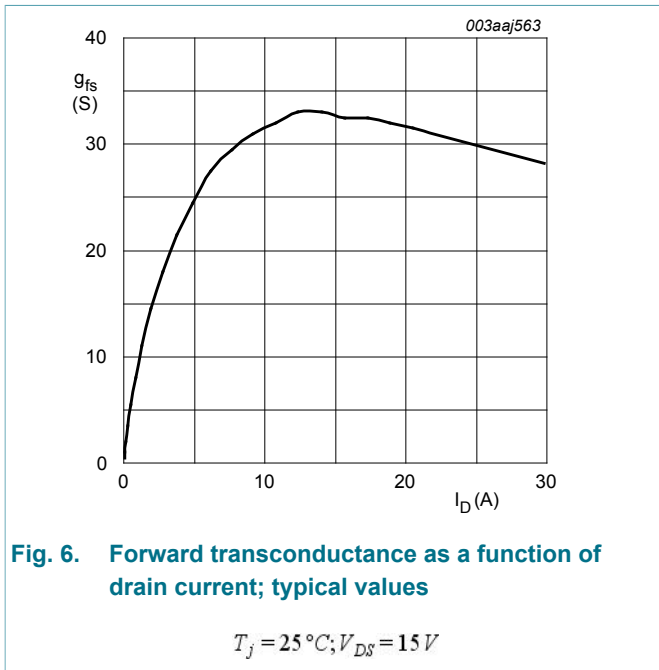
Fig. 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

10. Characteristics

Table 7. Characteristics

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---|----------------------------------|--|-----|-------|------|------------|
| Static characteristics FET1 and FET2 | | | | | | |
| $V_{(BR)DSS}$ | drain-source breakdown voltage | $I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 \text{ }^\circ C$ | 54 | - | - | V |
| | | $I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$ | 60 | - | - | V |
| $V_{GS(th)}$ | gate-source threshold voltage | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ }^\circ C;$ Fig. 10; Fig. 11 | 1.4 | 1.7 | 2.1 | V |
| | | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ }^\circ C;$ Fig. 10; Fig. 11 | 0.5 | - | - | V |
| | | $I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ }^\circ C;$ Fig. 10; Fig. 11 | - | - | 2.45 | V |
| I_{DSS} | drain leakage current | $V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ }^\circ C$ | - | - | 500 | μA |
| | | $V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ }^\circ C$ | - | 0.02 | 1 | μA |
| I_{GSS} | gate leakage current | $V_{GS} = -10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ }^\circ C$ | - | 2 | 100 | nA |
| | | $V_{GS} = 10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ }^\circ C$ | - | 2 | 100 | nA |
| R_{DSon} | drain-source on-state resistance | $V_{GS} = 5 \text{ V}; I_D = 5 \text{ A}; T_j = 25 \text{ }^\circ C;$ Fig. 12 | - | 30.5 | 35 | m Ω |
| | | $V_{GS} = 5 \text{ V}; I_D = 5 \text{ A}; T_j = 175 \text{ }^\circ C;$ Fig. 12; Fig. 13 | - | 65.27 | 79 | m Ω |
| | | $V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; T_j = 25 \text{ }^\circ C;$ Fig. 12 | - | 26.8 | 32 | m Ω |

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|--|------------------------------|--|-----|------|------|------|
| Dynamic characteristics FET1 and FET2 | | | | | | |
| $Q_{G(\text{tot})}$ | total gate charge | $I_D = 5 \text{ A}; V_{DS} = 48 \text{ V}; V_{GS} = 10 \text{ V};$ $T_j = 25 \text{ }^\circ\text{C};$ Fig. 14 ; Fig. 15 | - | 14.2 | - | nC |
| Q_{GS} | gate-source charge | | - | 1.2 | - | nC |
| Q_{GD} | gate-drain charge | | - | 3 | - | nC |
| C_{iss} | input capacitance | $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ }^\circ\text{C};$ Fig. 16 | - | 811 | 1081 | pF |
| C_{oss} | output capacitance | | - | 83 | 100 | pF |
| C_{rss} | reverse transfer capacitance | | - | 51 | 70 | pF |
| $t_{d(\text{on})}$ | turn-on delay time | $V_{DS} = 48 \text{ V}; R_L = 10 \text{ } \Omega; V_{GS} = 10 \text{ V};$ $R_{G(\text{ext})} = 5 \text{ } \Omega; T_j = 25 \text{ }^\circ\text{C}; I_D = 5 \text{ A}$ | - | 3.9 | - | ns |
| t_r | rise time | | - | 3.7 | - | ns |
| $t_{d(\text{off})}$ | turn-off delay time | | - | 20.5 | - | ns |
| t_f | fall time | | - | 10 | - | ns |
| Source-drain diode FET1 and FET2 | | | | | | |
| V_{SD} | source-drain voltage | $I_S = 10 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ }^\circ\text{C};$ Fig. 17 | - | 0.78 | 1.2 | V |
| t_{rr} | reverse recovery time | $I_S = 5 \text{ A}; dI_S/dt = -100 \text{ A}/\mu\text{s}; V_{GS} = 0 \text{ V};$ | - | 17.6 | - | ns |
| Q_r | recovered charge | $V_{DS} = 30 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$ | - | 12.1 | - | nC |



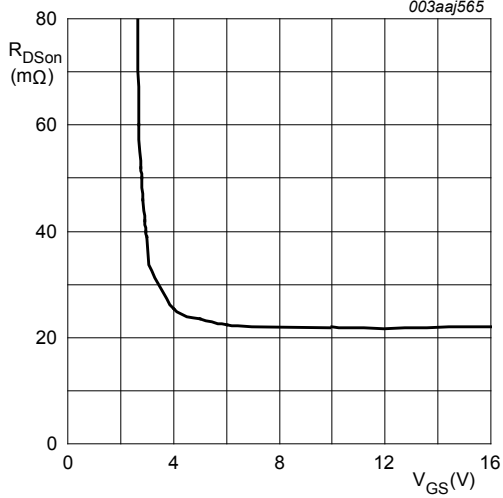


Fig. 8. Drain-source on-state resistance as a function of gate-source voltage; typical values

$T_j = 25^\circ\text{C}; I_D = 5\text{ A}$

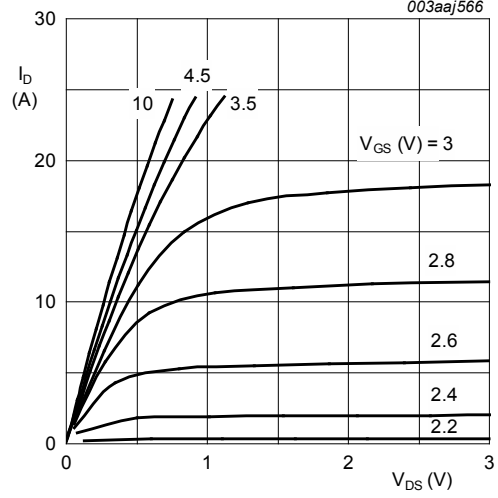


Fig. 9. Output characteristics: drain current as a function of drain-source voltage; typical values

$T_j = 25^\circ\text{C}$

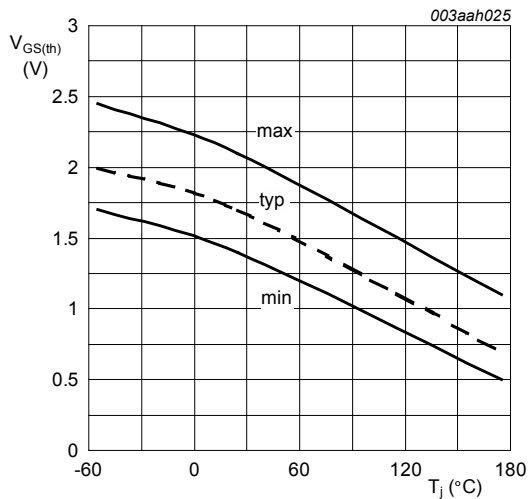


Fig. 10. Gate-source threshold voltage as a function of junction temperature

$I_D = 1\text{ mA}; V_{DS} = V_{GS}$

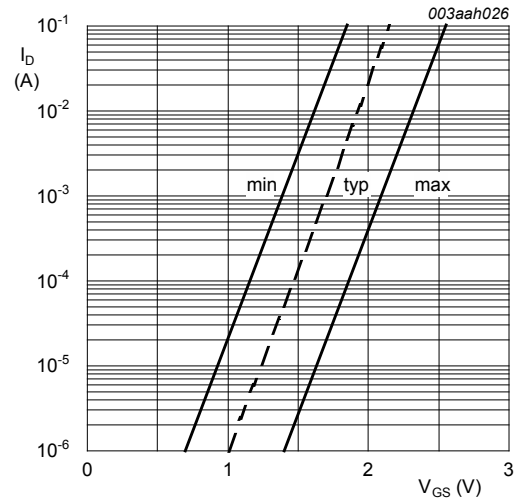


Fig. 11. Sub-threshold drain current as a function of gate-source voltage

$T_j = 25^\circ\text{C}; V_{DS} = 5\text{ V}$

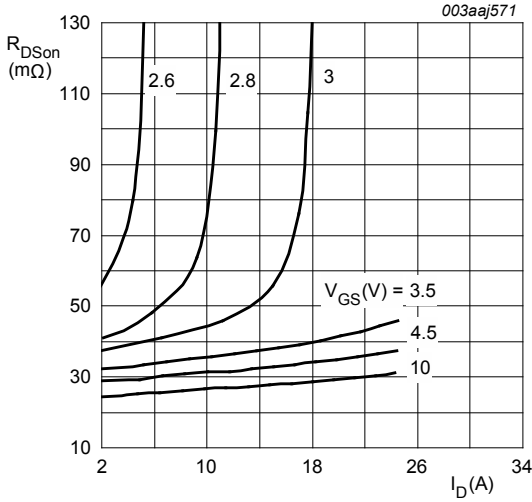


Fig. 12. Drain-source on-state resistance as a function of drain current; typical values

$T_j = 25^\circ\text{C}$

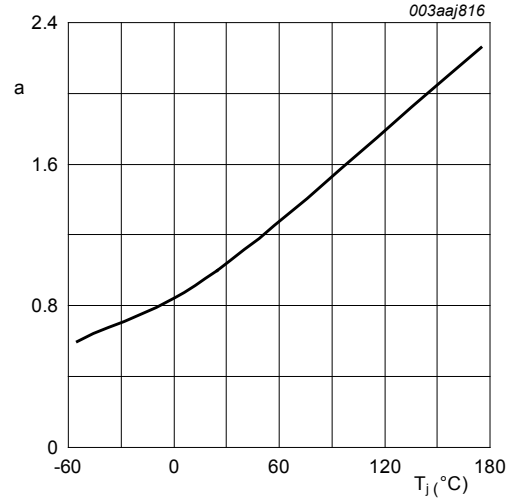


Fig. 13. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon}(25^\circ\text{C})}$$

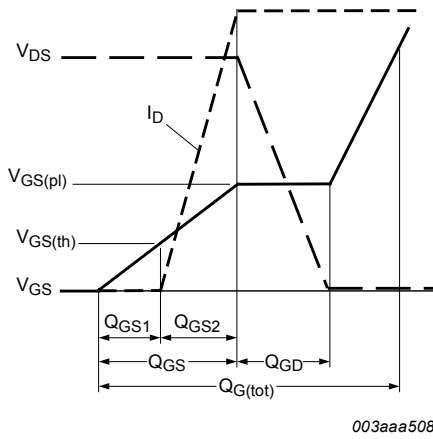


Fig. 14. Gate charge waveform definitions

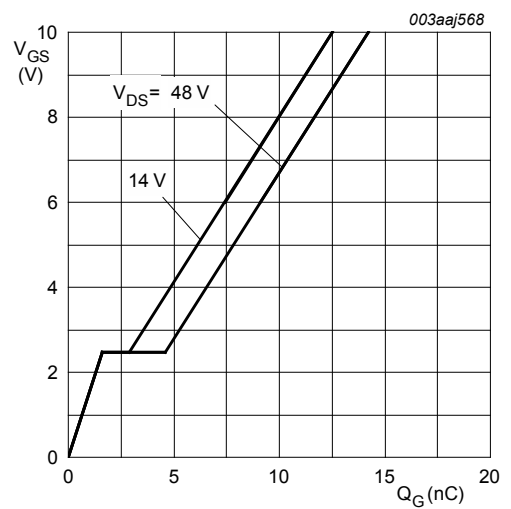


Fig. 15. Gate-source voltage as a function of gate charge; typical values

$T_j = 25^\circ\text{C}; I_D = 5\text{ A}$

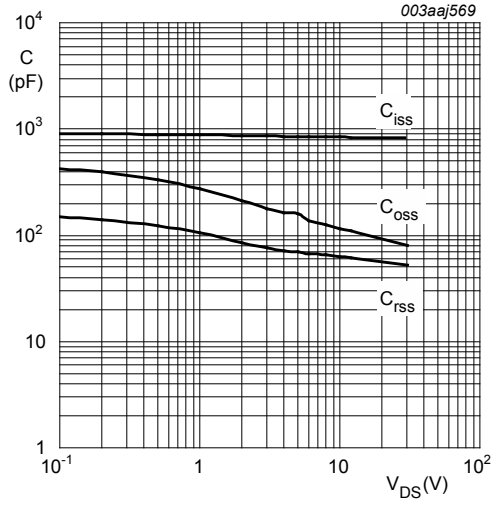


Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

$$V_{GS} = 0V; f = 1MHz$$

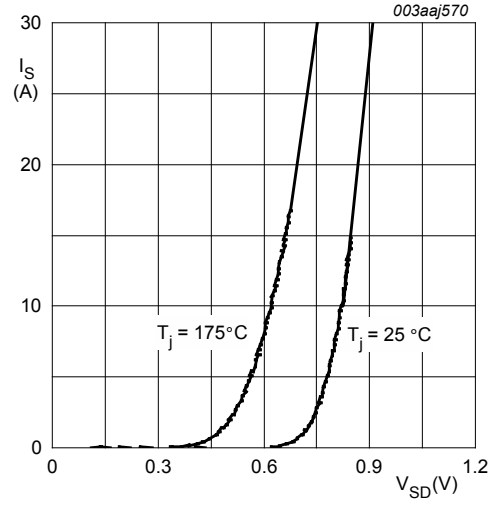


Fig. 17. Source current as a function of source-drain voltage; typical values

$$V_{GS} = 0V$$

11. Package outline

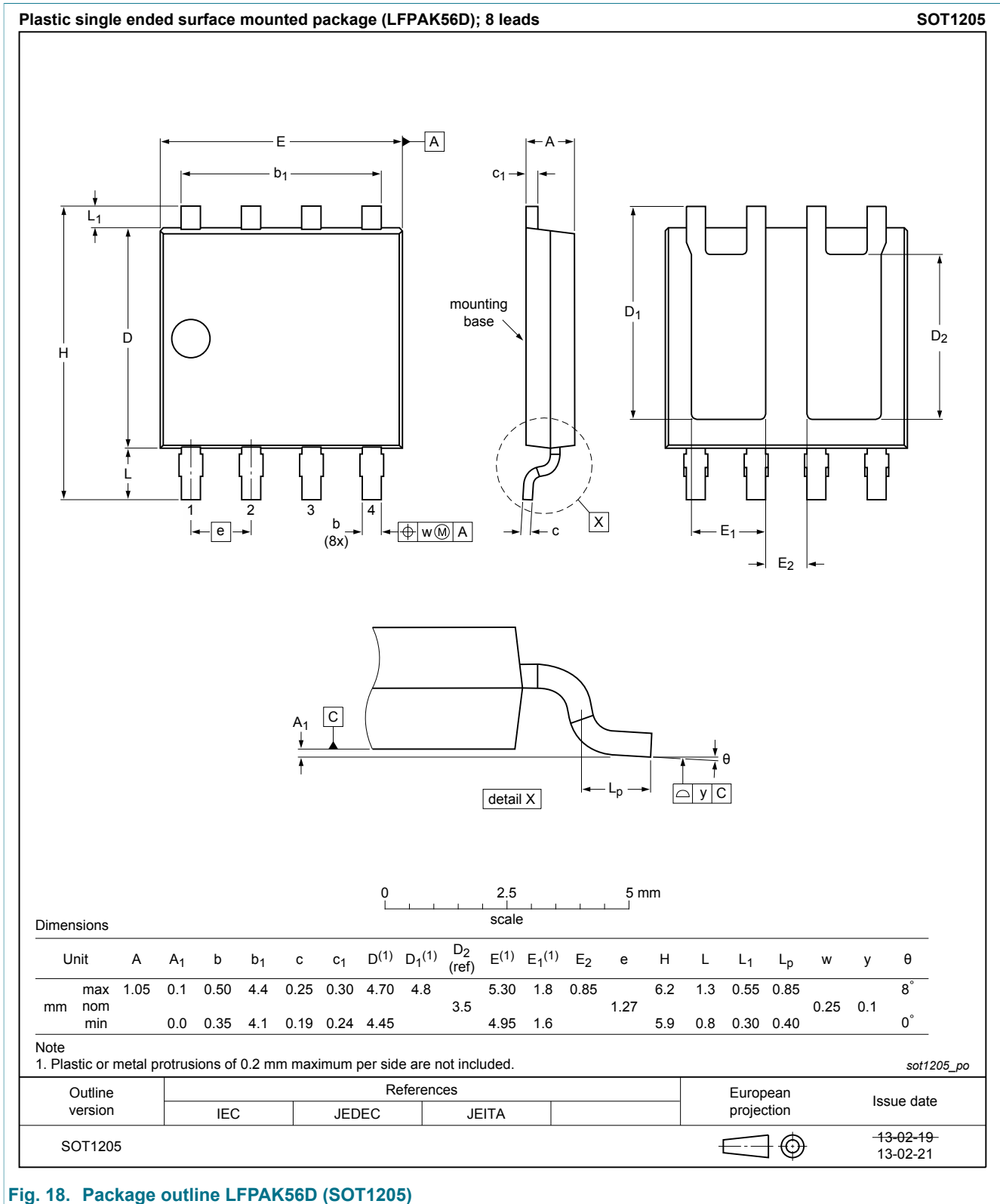


Fig. 18. Package outline LPAK56D (SOT1205)

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12.1 Data sheet status

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|--------------------------------|--------------------|---|
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